Electronic Supplementary Material (ESI) for Analytical Methods.
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Supporting Information

for

Screening for electrically conductive defects in thin functional films using electrochemiluminescence

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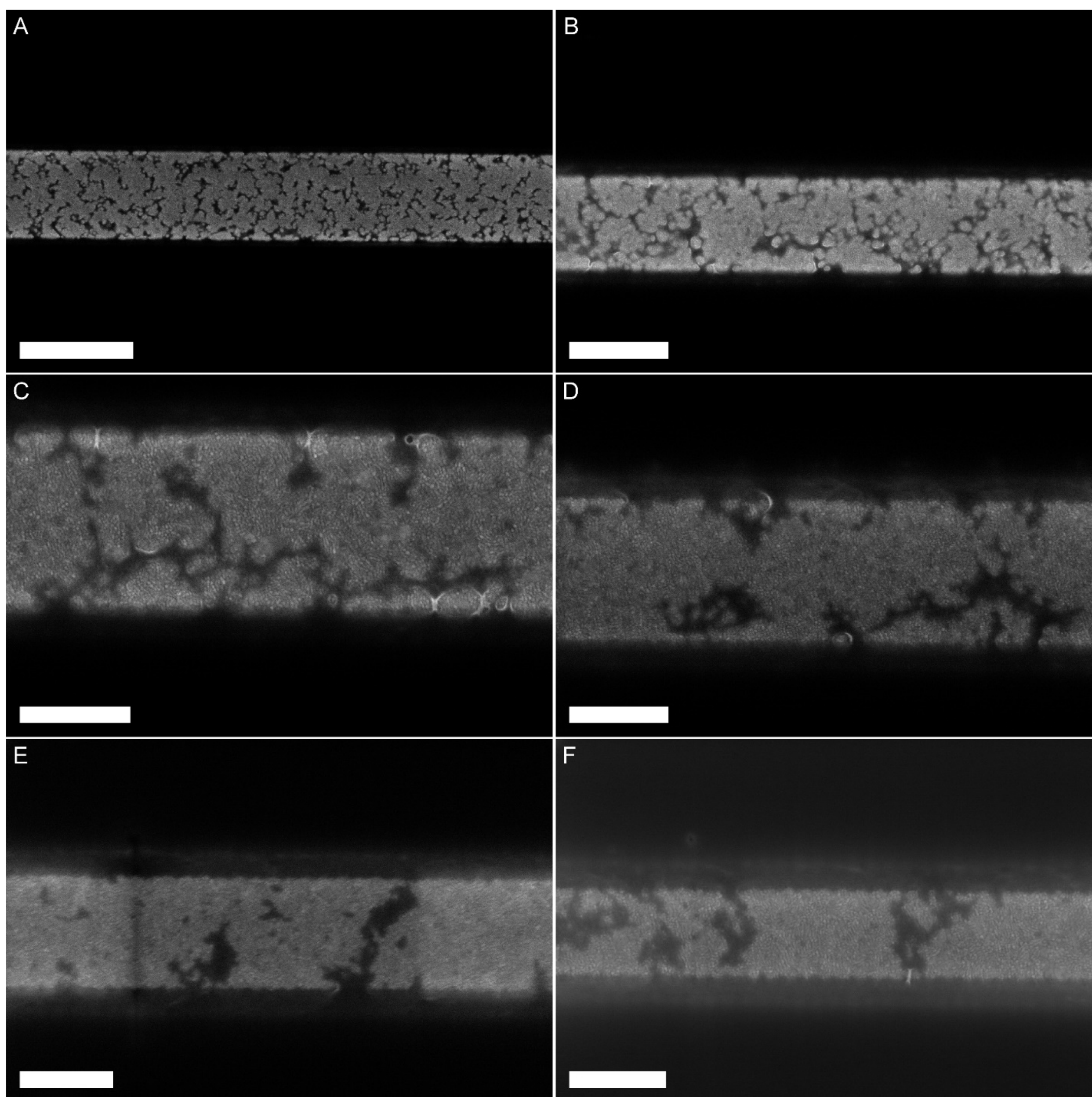

Figure S1: Scanning electron microscopy (SEM) images of lines of exposed indium tin oxide (ITO) with measured widths of (A) 1.46 µm (B) 0.93 µm (C) 0.77 µm (D) 0.72 µm (E) 0.60 µm (F) 0.44 µm. The background region is covered by a polymethylmethacrylate film. Scale bar for (A) is 2 µm. Scale bar for (B) is 1 µm. Scale bars for (C), (D), (E), and (F) are 500 nm.

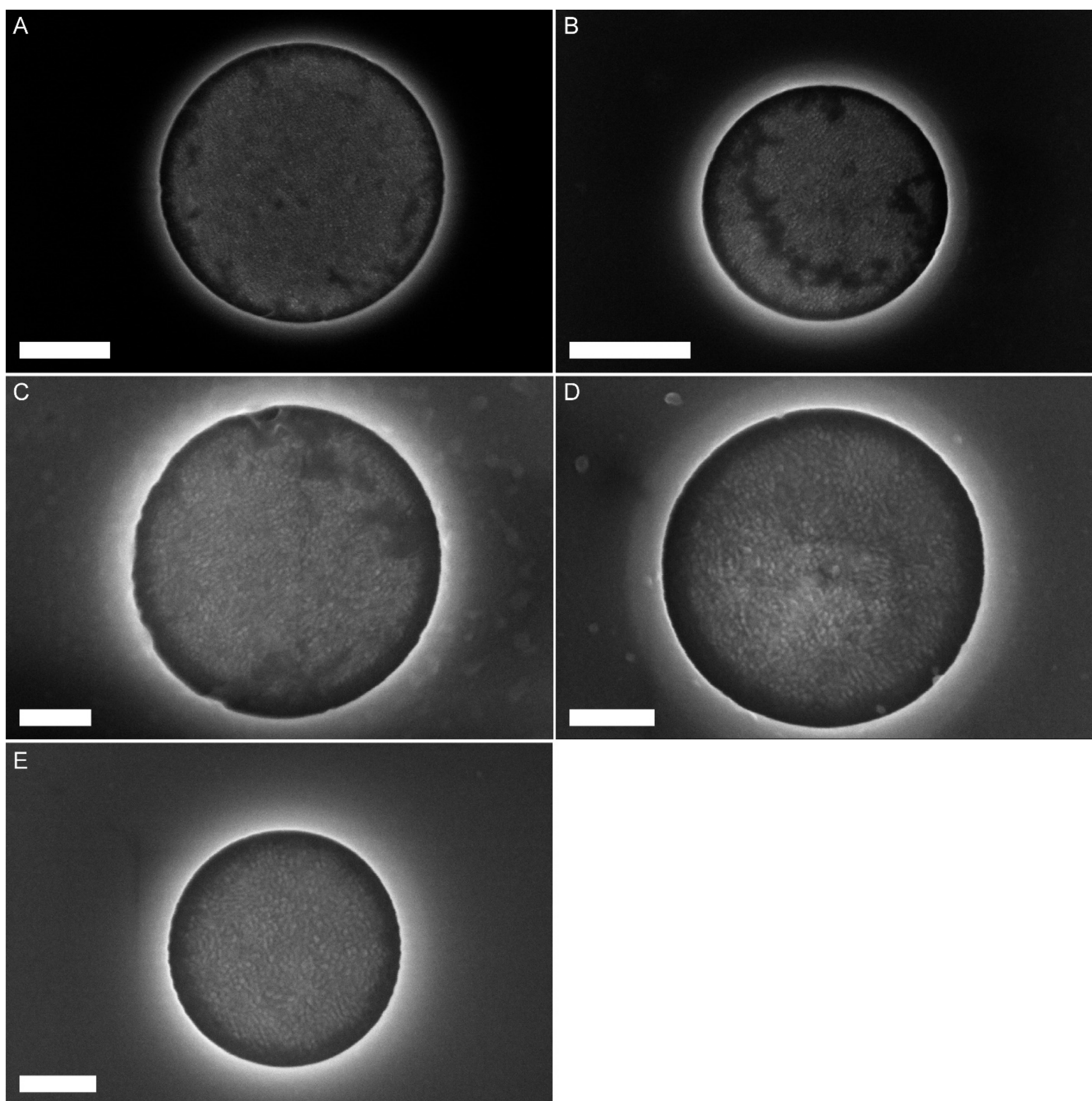

Figure S2: SEM images of circles of exposed ITO with measured diameters of (A) 1.63 µm (B) 1.03 µm (C) 0.90 µm (D) 0.78 µm (E) 0.62 µm. The background region is covered by a polymethylmethacrylate film. Scale bars for (A) and (B) are 500 nm. Scale bars for (C), (D), and (E) are 200 nm.